

## IEC TR 60068-3-15

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# TECHNICAL REPORT



Environmental testing – Part 3-15: Supporting documentation and guidance – Vacuum-assisted reflow soldering

INTERNATIONAL ELECTROTECHNICAL COMMISSION

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### CONTENTS

F(	DREWC	)RD	4
IN	TRODU	JCTION	6
1	Scop	pe	7
2	Norn	native references	7
3		ns and definitions	
4		s in solder joints	
•	4.1	Type of voids	
	4.2	Reasons for voids	
	4.3	Influence of voiding on solder joint performance	
5		ium-assisted soldering processes	
Ū	5.1	Purpose	
	5.2	Combination of soldering process with vacuum	
	5.3	Typical temperature-pressure-time curves	
	5.3.1	•••	
	5.3.2	<b>5</b>	
	5.3.3		
6		ct of vacuum when reflow soldering	
U	6.1	General	
	6.1.1		
	6.1.2	-	
	6.1.2	,	
	6.1.4	·	
	6.2	Components in the vacuum reflow soldering process	
	6.2.1		
	6.2.2		
7		ium equipment restrictions	
,		• •	
	7.1	General	
	7.2	Chamber size  Time to reach vacuum level	
	7.3 7.4	Cycle time	
		•	
0	7.5	Summary	
8	• •	cal defects after vacuum-assisted reflow soldering	
	8.1	Typical defect modes occurring at components	
	8.2	Component defect modes – summary	
	8.3	Soldering defect modes	
	8.3.1	11 5	
	8.3.2		
ь:	8.3.3	1 0	
Ві	bliogra	bhy	27
Fi	gure 1 -	- X-Ray examples of voids in solder joints in different SMD-Components	8
Fi	gure 2 -	- Reduction of voids with low flux soldering & preforms	8
Fi	gure 3 -	- Example of a product for vacuum-assisted soldering processes	10
		Typical profile – vacuum-assisted convection soldering	
	_	- Typical profile – vacuum-assisted vapour phase soldering	
	J =	,, r	

Figure 6 – Typical profile – vacuum-assisted contact soldering	13
Figure 7 – Vapour pressure curve of Galden®	15
Figure 8 – Pressures to be considered	16
Figure 9 – Vapour pressure curve of water	17
Figure 10 – Blow Hole Void in/out of metallization	20
Figure 11 – Gas bubbles at metallization interface	20
Figure 12 – Gas bubble caused by residues in metallization defect	21
Figure 13 – Blow out void in solder meniscus	21
Figure 14 – Aluminium electrolytic capacitors with non-solid electrolyte, bulged	22
Figure 15 – Composite housing bursts in case of overpressure	22
Figure 16 – Housing mainly made of plastic bursts in case of overpressure	23
Figure 17 – Relay lock (polymer dot) blown off	23
Figure 18 – Housing with adhesive joint bursts in case of overpressure	24
Figure 19 – An example of bridging on BGA during vacuum assisted soldering	25
Figure 20 – Optimization with stepwise applying of vacuum to reduce bridging	25
Figure 21 – Splattering due to explosive outgassing from the solder joint	26
Table 1 – Combination of soldering processes with vacuum	10
Table 2 – Molar mass	17
Table 3 – Combination of soldering processes with vacuum	19

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## Part 3-15: Supporting documentation and guidance – Vacuum-assisted reflow soldering

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The text of this Technical Report is based on the following documents:

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Full information on the voting for its approval can be found in the report on voting indicated in the above table.

The language used for the development of this Technical Report is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at <a href="https://www.iec.ch/members\_experts/refdocs">www.iec.ch/members\_experts/refdocs</a>. The main document types developed by IEC are described in greater detail at <a href="https://www.iec.ch/publications">www.iec.ch/publications</a>.

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#### INTRODUCTION

As defined in ISO 857-2, reflow soldering is a joining process using an additional metal (solder) with a liquidus temperature of 450 °C or less, in which solder paste or preforms are reflowed.

Reflow soldering can be carried out with the technical processes of convection (air or nitrogen), condensation (vapour phase), radiation (e.g. infrared) or contact heat.

Sometimes it is not possible to achieve the required void level for an assembly only with methods listed above despite the use of all technical possibilities.

Regarding void-induced asymmetrical stress constellations, a reduction of voiding can lead to a mitigated stress condition within the solder joints.

Various technical requirements only tolerate very small void dimensions. To achieve these requirements, vacuum-assisted soldering can be applied with the above mentioned reflow soldering processes.

In some product applications, a hermetic seal is required. The reliable fulfilment of this requirement is very demanding to the process technology especially complex assemblies. Vacuum-assisted soldering creates significantly more consistency in the results here.

Further benefits of vacuum-assisted soldering are improved thermal management or high frequency performance (contour adaptation, mitigation of blow holes).

Vacuum-assisted soldering, however, requires a different equipment with more complex structure and process control. Since the vacuum process has an impact on the process time, the suitability of the components and solder paste that are used need to be checked.

#### **ENVIRONMENTAL TESTING -**

## Part 3-15: Supporting documentation and guidance – Vacuum-assisted reflow soldering

#### 1 Scope

This part of IEC 60068 describes vacuum-assisted soldering considering the thermal profiling, soldering methods, suitability of the components and vacuum features of soldering systems. It is based on practical experiences from manufacturers, component, material, and soldering systems suppliers. It supports manufacturers by providing information about the functionality of vacuum and effect of vacuum on components performance.

#### 2 Normative references

There are no normative references in this document.